

Notice of References Cited	Application/Control No. 10/595,686	Applicant(s)/Patent Under Reexamination CHOY ET AL.	
	Examiner REBECCA LEE	Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Greene et al. "low-Temperature Wafer-Scale production of ZnO nanowire Arrays", Angew. Chem. Int. Ed. 2003, 42, 3031-3034
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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